

S54H71-A.F.W • N74H71-A.F

DIGITAL 54/74 TTL SERIES

DESCRIPTION

These J-K flip-flops are based on the master-slave principle. The AND-OR gate inputs for entry into the master section are controlled by the clock pulse. The clock pulse also regulates the circuitry which connects the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from AND-OR gate inputs to master
3. Disable AND-OR gate inputs
4. Transfer information from master to slave.

Logical state of J and K inputs must not be allowed to change when the clock pulse is in a high state.

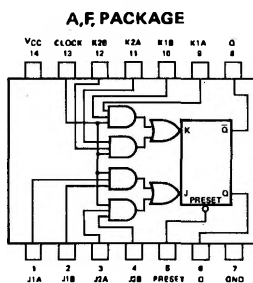
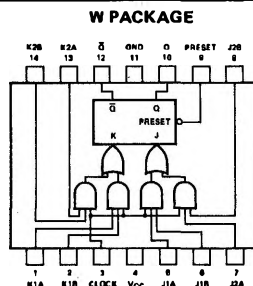
TRUTH TABLE

t_n		t_{n+1}
J	K	Q
0	0	Q_n
0	1	0
1	0	1
1	1	$\bar{Q}_n$

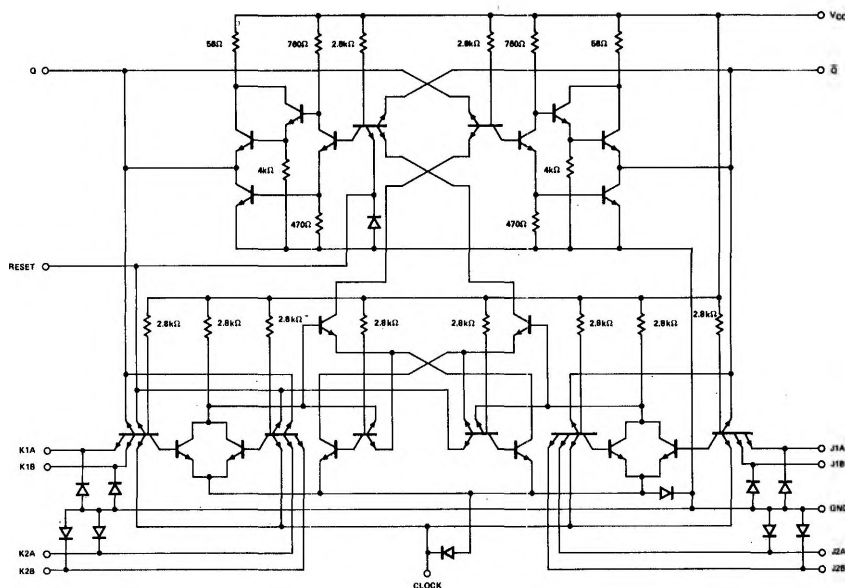
NOTES:

1. $J = (J1A \bullet J1B) + (J2A \bullet J2B)$
2. $K = (K1A \bullet K1B) + (K2A \bullet K2B)$
3. t_n = Bit time before clock pulse.
4. t_{n+1} = Bit time after clock pulse.

PIN CONFIGURATIONS



SCHEMATIC



NOTE: Component values shown are nominal.

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RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage V_{CC} : S54H71 Circuits	4.5	5	5.5	V
N74H71 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, T_A : S54H71 Circuits	-55	25	125	°C
N74H71 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_{p(\text{clock})}$	12			ns
Width of Preset Pulse, $t_{p(\text{preset})}$	16			ns
Input Setup Time, t_{setup} (See Above)	$>t_{p(\text{clock})}$			
Input Hold Time, t_{hold}	0			

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP†	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal		2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal				0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{\text{load}} = -500\mu\text{A}$	2.4			V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{\text{sink}} = 20\text{mA}$			0.4	V
$I_{in(0)}$ J1B, J2A, J2B, K1A, K1B, K2A, or K2B	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-2	mA
$I_{in(0)}$ Logical 0 level input current at preset	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-6	mA
$I_{in(0)}$ Logical 0 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-4	mA
$I_{in(1)}$ J1B, J2A, J2B, K1A, K1B, K2A, or K2B	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$			50	μA
$I_{in(1)}$ Logical 1 level input current at preset	$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			1	mA
$I_{in(1)}$ Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$			150	μA
$I_{in(1)}$ Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			1	mA
I_{OS} Short-circuit output current **	$V_{CC} = \text{MAX}, V_{in} = 0$	-40		-100	mA
I_{CC} Supply current	$V_{CC} = \text{MAX}$		19	30	mA

SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f_{clock} Maximum clock frequency	$C_L = 25\text{ pF}, R_L = 280\Omega$	25	30		MHz
t_{pd1} Propagation delay time to logical 1 level from preset to output	$C_L = 25\text{ pF}, R_L = 280\Omega$		6	13	ns
t_{pd0} Propagation delay time to logical 0 level from preset to output	$C_L = 25\text{ pF}, R_L = 280\Omega$		12	24	ns
t_{pd1} Propagation delay time to logical 1 level from clock to output	$C_L = 25\text{ pF}, R_L = 280\Omega$	6	14	21	ns
t_{pd0} Propagation delay time to logical 0 level from clock to output	$C_L = 25\text{ pF}, R_L = 280\Omega$	10	22	27	ns

* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

** Not more than one output should be shorted at a time, and duration of short-circuit test should not exceed 1 second.

† All typical values are at $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$.